



Click [here](#) for the 3D model.

General Information

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|--------------------------|-----------------------------------------------------|
| Series | SMD Auto COG |
| Style | SMD Chip |
| Description | SMD, MLCC, Ultra-Stable, Low Loss, Automotive Grade |
| Features | Ultra-Stable, Low Loss, Automotive Grade |
| RoHS | Yes |
| Termination | Tin |
| Marking | No |
| Qualifications | AEC-Q200 |
| Typical Component Weight | 52 mg |
| Shelf Life | 78 Weeks |
| MSL | 1 |

Dimensions

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|----------------------|------------------|
| L | 3.2mm +/-0.2mm |
| W | 2.5mm +/-0.2mm |
| T | 1.55mm +/-0.15mm |
| S | 1.5mm MIN |
| B | 0.5mm +/-0.25mm |
| Case Code (EIA / mm) | 1210 / 3225 |

Packaging Specifications

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|--------------------|--------------------------|
| Packaging | T&R, 180mm, Plastic Tape |
| Packaging Quantity | 2000 |

Specifications

| | |
|--------------------------------------------------------------------|------------------------|
| Capacitance | 0.15 uF |
| Measurement Condition | 1 kHz 1.0Vrms |
| Tolerance | 5% |
| Voltage DC | 25 VDC |
| Dielectric Withstanding Voltage | 62.5 VDC |
| Temperature Range | -55/+125°C |
| Temp. Coefficient | COG |
| Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC) | 30 ppm/C, 1kHz 1.0Vrms |
| Dissipation Factor | 0.1% 1 kHz 1.0Vrms |
| Aging Rate | 0% Loss/Decade Hour |
| Insulation Resistance | 6.6667 GOhms |

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